

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/722,951 BEDNARIK ET AL.	
		Examiner	Art Unit Vivian Chen	1773 Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,787,205	09-2004	Aho et al.	428/34.2
*	B	US-5,360,663	11-1994	Moteki et al.	442/62
*	C	US-6,358,576	03-2002	Adur et al.	428/34.2
*	D	US-5,178,960	01-1993	Cook, John W.	428/461
*	E	US-6,903,161	06-2005	Morris, Barry Alan	525/191
*	F	US-6,540,862	04-2003	Calvert et al.	156/244.17
*	G	US-6,645,584	11-2003	Kuusipalo et al.	428/34.2
*	H	US-6,544,722	04-2003	Bouwstra et al.	430/349
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	EP 421103 A	04-1991	EP	Gench et al	----
*	O	JP 10-151655	06-1998	JP	Harada et al	----
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.